

Search Notes



Application/Control No.

10/529,742

Examiner

Kin-Chan Chen

Applicant(s)/Patent under
Reexamination

SHIHO ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
438	690	1/22/2007	KCC
438	691		
438	692		
252	79.1		
451	6		
451	41		
451	533	1/22/2007	KCC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
East keywords search USPAT, uspg-pub. Epo, Jpo, Derwent IBM-TDB - inventor search	1/22/2007	KCC